

<b>Notice of References Cited</b>		Application/Control No. 09/998,030	Applicant(s)/Patent Under Reexamination DEINDL ET AL.	
		Examiner Satish S. Rampuria	Art Unit 2124	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2001/0000814 A1	05-2001	Montgomery et al.	710/10
	B	US-6,547,150 B1	04-2003	Deo et al.	235/492
	C	US-6,157,966 A	12-2000	Montgomery et al.	710/8
	D	US-2001/0039587 A1	11-2001	UHLER et al.	709/229
	E	US-2002/0170033 A1	11-2002	CHEN, ZHIQUN	717/124
	F	US-6,701,514 B1	03-2004	Haswell et al.	717/115
	G	US-5,615,331 A	03-1997	Toorians et al.	714/9
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP-A-0356237	02-1990	Europe	Shinagawa, Toru	G07 F 7/10
	O	FR-002667419	04-1992	France	Sourenian et al.	G06 K 019/073
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	<a href="http://java.sun.com/products/javacard/smartcard.html">http://java.sun.com/products/javacard/smartcard.html</a> , Smart Card Overview, unknown, Internet, Page 1
	V	Kirovski et al., Cut-Based functional Debugging for programmable system-on-chip, Feb 2000, IEEE, Pages 40-51
	W	Chen, Java Card Technology for smart cards, June 2000, Sun Microsystems, Pages 11-16
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.